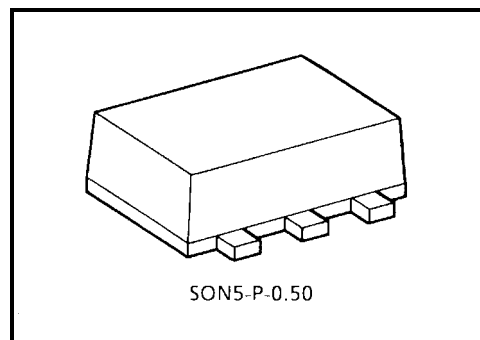


TC7SZ08AFE

2 Input AND Gate

Features

- High output drive: ± 24 mA (typ.)
@ $V_{CC} = 3$ V
- Super high speed operation: $t_{PD} 2.7$ ns (typ.)
@ $V_{CC} = 5$ V, 50 pF
- Operation voltage range: $V_{CC} (opr) = 1.8 \sim 5.5$ V
- Supply voltage data retention: $V_{CC} = 1.5 \sim 5.5$ V
- Latch-up performance: ± 500 mA
- ESD performance: Human body model $> \pm 2000$ V
Machine model $> \pm 200$ V
- Power down protection is provided on all inputs.
- Matches the performance of TC74LCX series when operated at 3.3 V V_{CC}
- Input rise and fall time (t_r , t_f) (recommended operation condition)
@ $V_{CC} = 1.8$ V, 2.5 V ± 0.2 V: 0~20 ns/V
@ $V_{CC} = 3.3$ V ± 0.3 V: 0~10 ns/V
@ $V_{CC} = 5.5$ V ± 0.5 V: 0~5 ns/V



Weight: 0.003 g (typ.)

Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	$-0.5 \sim 6$	V
DC input voltage	V_{IN}	$-0.5 \sim 6$	V
DC output voltage	V_{OUT}	$-0.5 \sim V_{CC} + 0.5$	V
Input diode current	I_{IK}	± 20	mA
Output diode current	I_{OK}	± 20	mA
DC output current	I_{OUT}	± 50	mA
DC V_{CC} /ground current	I_{CC}	± 50	mA
Power dissipation	P_D	150	mW
Storage temperature	T_{stg}	$-65 \sim 150$	$^\circ\text{C}$
Lead temperature (10 s)	T_L	260	$^\circ\text{C}$

Electrical Characteristics
DC Characteristics

Characteristics	Symbol	Test Circuit	Test Condition		V _{CC} (V)	Ta = 25°C			Ta = -40~85°C		Unit
						Min	Typ.	Max	Min	Max	
High-level input voltage	V _{IH}	—	—		1.8	0.75 × V _{CC}	—	—	0.75 × V _{CC}	—	V
					2.3-5.5	0.7 × V _{CC}	—	—	0.7 × V _{CC}	—	
Low-level input voltage	V _{IL}	—	—		1.8	—	—	0.25 × V _{CC}	—	0.25 × V _{CC}	V
					2.3-5.5	—	—	0.3 × V _{CC}	—	0.3 × V _{CC}	
High-level output voltage	V _{OH}	—	V _{IN} = V _{IH}	I _{OH} = -100 μA	1.8	1.7	1.8	—	1.7	—	V
					2.3	2.2	2.3	—	2.2	—	
					3.0	2.9	3.0	—	2.9	—	
					4.5	4.4	4.5	—	4.4	—	
				I _{OH} = -8 mA	2.3	1.9	2.15	—	1.9	—	
				I _{OH} = -16 mA	3.0	2.4	2.8	—	2.4	—	
				I _{OH} = -24 mA	3.0	2.3	2.68	—	2.3	—	
				I _{OH} = -32 mA	4.5	3.8	4.2	—	3.8	—	
Low-level output voltage	V _{OL}	—	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 100 μA	1.8	—	0	0.1	—	0.1	V
					2.3	—	0	0.1	—	0.1	
					3.0	—	0	0.1	—	0.1	
					4.5	—	0	0.1	—	0.1	
				I _{OL} = 8 mA	2.3	—	0.1	0.3	—	0.3	
				I _{OL} = 16 mA	3.0	—	0.15	0.4	—	0.4	
				I _{OL} = 24 mA	3.0	—	0.22	0.55	—	0.55	
				I _{OL} = 32 mA	4.5	—	0.22	0.55	—	0.55	
Input leakage current	I _{IN}	—	V _{IN} = 5.5 V or GND		0-5.5	—	—	±1	—	±10	μA
Quiescent supply current	I _{CC}	—	V _{IN} = V _{CC} or GND		5.5	—	—	2	—	20	μA

AC Characteristics (input: $t_r = t_f = 3\text{ ns}$)

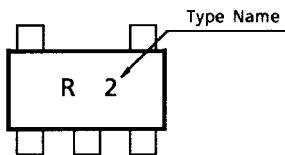
Characteristics	Symbol	Test Circuit	Test Condition	V _{CC} (V)	Ta = 25°C			Ta = -40~85°C		Unit
					Min	Typ.	Max	Min	Max	
Propagation delay time	t_{PLH} t_{PHL}	—	$C_L = 15\text{ pF}$, $R_L = 1\text{ M}\Omega$	1.8	2.0	5.2	9.5	2.0	10.5	ns
				2.5 ± 0.2	0.8	3.4	7.0	0.8	7.5	
				3.3 ± 0.3	0.5	2.6	4.7	0.5	5.0	
				5.0 ± 0.5	0.5	2.2	4.1	0.5	4.4	
			$C_L = 50\text{ pF}$, $R_L = 500\text{ }\Omega$	3.3 ± 0.3	1.5	3.3	5.2	1.5	5.5	
				5.0 ± 0.5	0.8	2.7	4.5	0.8	4.8	
Input capacitance	C_{IN}	—	—	0-5.5	—	4	—	—	—	pF
Power dissipation capacitance	C_{PD}	—	(Note)	3.3	—	19	—	—	—	pF
				5.5	—	26	—	—	—	

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

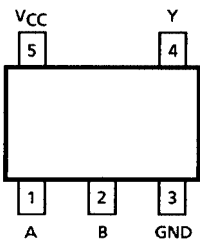
Average operating current can be obtained by the equation.

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

Marking



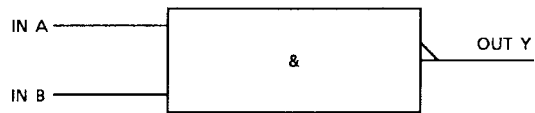
Pin Assignment (top view)



Truth Table

A	B	Y
L	L	L
L	H	L
H	L	L
H	H	H

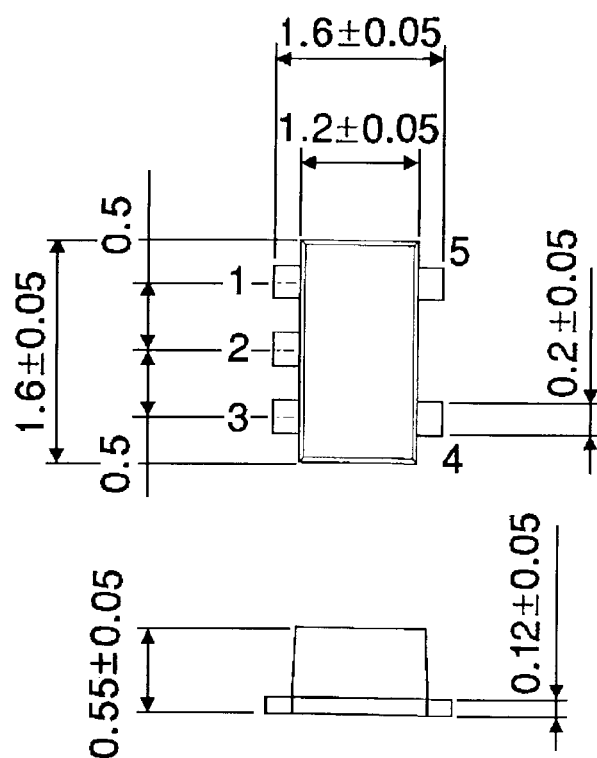
Logic Diagram



Package Dimensions

SON5-P-0.50

Unit : mm



Weight: 0.003 g (typ.)

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000707EBA

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